

<b>Notice of References Cited</b>	Application/Control No. 10/594,774		Applicant(s)/Patent Under Reexamination SHINDO ET AL.	
	Examiner MARY A. KAY		Art Unit 2426	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0154217	08-2003	Kinno et al.	707/104.1
*	B	US-2002/0144007	10-2002	Shteyn, Yevgeniy Eugene	709/313
*	C	US-6,678,332	01-2004	Gardere et al.	375/240.26
*	D	US-6,360,218	03-2002	Zander et al.	1/1
*	E	US-2004/0249861	12-2004	Hoshino et al.	707/104.1
*	F	US-7,134,074	11-2006	Munetsugu et al.	715/204
*	G	US-2002/0166123	11-2002	Schrader et al.	725/58
*	H	US-7,272,843	09-2007	Nejime et al.	725/32
*	I	US-2006/0041915	02-2006	Dimitrova et al.	725/081
*	J	US-7,634,795	12-2009	Dureau, Vincent	725/80
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.